

INTERNATIONAL STANDARD

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**Fibre optic communication subsystem test procedures –
Part 2-8: Digital systems – Determination of low BER using Q-factor
measurements**

**Procédures d'essai des sous-systèmes de télécommunications fibroniques –
Partie 2-8: Systèmes numériques – Détermination de faibles valeurs de BER en
utilisant des mesures du facteur Q**



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CONTENTS

FOREWORD	4
1 Scope	6
2 Normative references	6
3 Terms, definitions, and abbreviated terms	6
3.1 Terms and definitions.....	6
3.2 Abbreviated terms.....	7
4 Measurement of low bit-error ratios	7
4.1 General considerations	7
4.2 Background to Q-factor	8
5 Variable decision threshold method	10
5.1 Overview.....	10
5.2 Apparatus	13
5.3 Sampling and specimens	13
5.4 Procedure	13
5.5 Calculations and interpretation of results	15
5.5.1 Sets of data	15
5.5.2 Convert BER using inverse error function	16
5.5.3 Linear regression.....	17
5.5.4 Standard deviation and mean	18
5.5.5 Optimum decision threshold.....	18
5.5.6 BER optimum decision threshold	18
5.5.7 BER non-optimum decision threshold	19
5.5.8 Error bound	19
5.6 Test documentation	19
5.7 Specification information.....	19
6 Variable optical threshold method.....	19
6.1 Overview.....	19
6.2 Apparatus	20
6.3 Items under test.....	20
6.4 Procedure for basic optical link	20
6.5 Procedure for self-contained system	21
6.6 Evaluation of results	22
Annex A (normative) Calculation of error bound in the value of Q	24
Annex B (informative) Sinusoidal interference method	26
B.1 Overview.....	26
B.2 Apparatus	26
B.3 Sampling and specimens	26
B.4 Procedure	27
B.4.1 Optical sinusoidal interference method	27
B.4.2 Electrical sinusoidal interference method.....	28
B.5 Calculations and interpretation of results	29
B.5.1 Mathematical analysis	29
B.5.2 Extrapolation	29
B.5.3 Expected results	30
B.6 Documentation.....	31

B.7	Specification information	31
	Bibliography	32
Figure 1	– Sample eye diagram showing patterning effects	9
Figure 2	– More accurate measurement technique using a DSO that samples noise statistics between eye centres	10
Figure 3	– Bit error ratio as a function of decision threshold level	11
Figure 4	– Plot of Q-factor as a function of threshold voltage	12
Figure 5	– Set-up for the variable decision threshold method	14
Figure 6	– Set-up of initial threshold level (approximately at the centre of the eye)	14
Figure 7	– Effect of optical bias	20
Figure 8	– Set-up for optical link or device test	21
Figure 9	– Set-up for system test	21
Figure 10	– Extrapolation of log BER as a function of bias	23
Figure B.1	– Set-up for the sinusoidal interference method by optical injection	27
Figure B.2	– Set-up for the sinusoidal interference method by electrical injection	29
Figure B.3	– BER result from the sinusoidal interference method (data points and extrapolated line)	30
Figure B.4	– BER versus optical power for three methods	31
Table 1	– Mean time for the accumulation of 15 errors as a function of BER and bit rate	7
Table 2	– BER as a function of threshold voltage	16
Table 3	– f_i as a function of D_i	17
Table 4	– Values of linear regression constants	18
Table 5	– Mean and standard deviation	18
Table 6	– Example of optical bias test	22
Table B.1	– Results for sinusoidal injection	28

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FIBRE OPTIC COMMUNICATION SUBSYSTEM TEST PROCEDURES –**Part 2-8: Digital systems –
Determination of low BER using Q-factor measurements**

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This second edition cancels and replaces the first edition published in 2003. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) correction of errors in Formula (8) in 5.5.2 and in a related formula in 5.5.3;
- b) correction of errors in the references to clauses, subclauses, figures, procedures, and in the Bibliography;
- c) alignment of the terms and definitions in 3.1 with those in IEC 61281-1.

The text of this International Standard is based on the following documents:

FDIS	Report on voting
86C/1708/FDIS	86C/1711/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/standardsdev/publications.

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